

STQ1NE10L

N-channel 100V - 0.3Ω - 1A - TO-92 STripFET™ Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STQ1NE10L	100V	<0.4Ω	1A

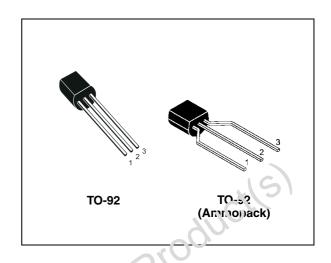
- Exceptional high dv/dt capability
- 100% avalanche tested
- Avalanche rugged technology
- Low threshold drive

Description

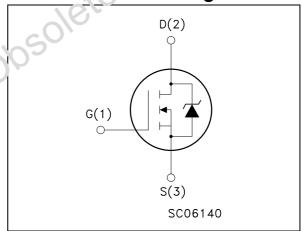
This Power MOSFET is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

olete Productle **Applications**

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STQ1NE10L	Q1NE10L	TO-92	Tube
STQ1NE10L-AP	STQ1NE10L-AP Q1NE10L		Ammopak

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STQ1NE10L **Electrical ratings**

Electrical ratings 1

Table 1. **Absolute maximum ratings**

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	100	٧
V_{GS}	Gate-source voltage	± 16	V
I _D	Drain current (continuous) at T _C = 25°C	1	Α
I _D	Drain current (continuous) at T _C =100°C	0.6	Α
I _{DG}	Drain gate current (continuous)	± 50	mA
I _{GS}	Gate source current (continuous)	± 50	mA
I _{DM} ⁽¹⁾	Drain current (pulsed)	4	Α
P _{TOT} ⁽²⁾	Total dissipation at $T_C = 25^{\circ}C$	3	W
	Derating factor	0.025	W/°C
dv/dt ⁽³⁾	Peak diode recovery voltage slope	6	V/ns
E _{AS} ⁽⁴⁾	Single pulse avalanche energy	400	mJ
T _{stg}	Storage temperature	EE to 150	°C
T _J	Operating junction temperature	-55 to 150	

- neiated to Rthj -l 3. $I_{SD} \le 1A$, di/dt $\le 200A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_J \le T_{JMAX}$ 4. Starting $T_J = 25$ °C, $I_D = 1A$, $V_{DD} = 50V$

	Symbol	Parameter	Value	Unit
	R _{thJC}	Thermal resistance junction-case max	40	°C/W
	R _{thJA}	Thermal resistance junction-ambient max	125	°C/W
	Tı	Maximum lead temperature for soldering purpose	260	°C
Obsole	te			

Electrical characteristics STQ1NE10L

2 Electrical characteristics

(T_{CASE} = 25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
V _{(BR)DG}	Clamped voltage	$I_D = 250 \mu A, V_{GS} = 0$	100			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = Max rating$ $V_{DS} = Max rating$ $T_C = 125^{\circ}C$			1 10	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ±16 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		2.5	V
D	Static drain-source ON	$V_{GS} = 10 \text{ V}, I_D = 0.5 \text{ A}$		0.30	0.40	Ω
R _{DS(on)}	resistance	$V_{GS} = 5 \text{ V}, I_D = 0.5 \text{ A}$		0.35	0.45	Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs}	Forward transconductance	$V_{DS} = 15 \text{ V}, I_{D} = 0.5 \mu\text{A}$		2		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{MHz}, V_{GS} = 0$		345 45 20		pF pF pF
t _{r(on)} t _f	Turn-on time Rise time	$V_{DD} = 50 \text{ V}, I_D = 0.5 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ Figure 12		11 12		ns ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	$V_{DD} = 50$ V, $I_D = 0.5$ A $R_G = 4.7\Omega$, $V_{GS} = 5$ V Figure 12		20 13		ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 80 \text{ V}, I_D = 1\text{A},$ $V_{GS} = 5\text{V}$ Figure 13		7 1.5 3.5		nC nC nC

Table 5. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD}	Source-drain current				1	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				4	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =1A, V _{GS} =0			1.5	٧
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 1A,$ $di/dt = 100A/\mu s,$ $V_{DD} = 30V, T_J = 100^{\circ}C$		52 90 3.5		ns nC A

- 1. Pulse width limited by safe operating area
- 2. Pulsed: pulse duration=300µs, duty cycle 1.5%

Electrical characteristics STQ1NE10L

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance

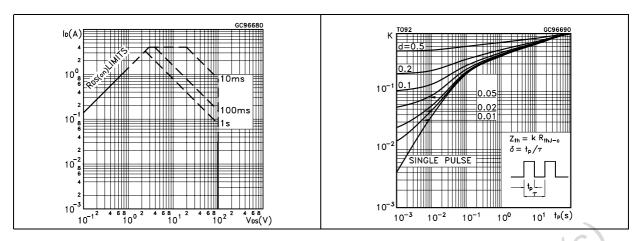


Figure 3. Output characteristics

Figure 4. Transfer characteristics

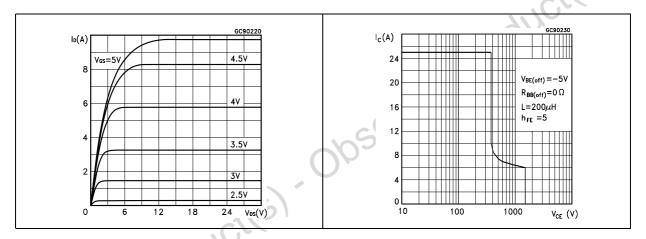


Figure 5. Transconductance

Figure 6. Static drain-source on resistance

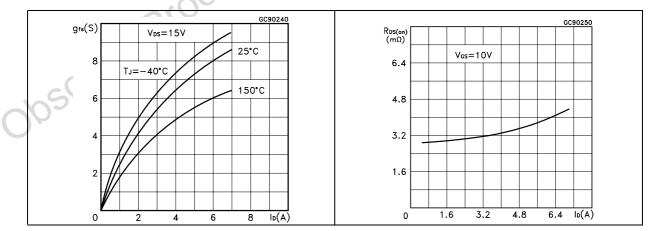


Figure 7. Gate charge vs. gate-source voltage Figure 8. Capacitance variations

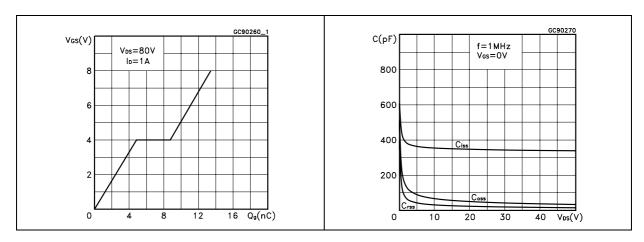


Figure 9. Normalized gate threshold voltage Figure 10. Normalized on resistance vs. vs. temperature temperature

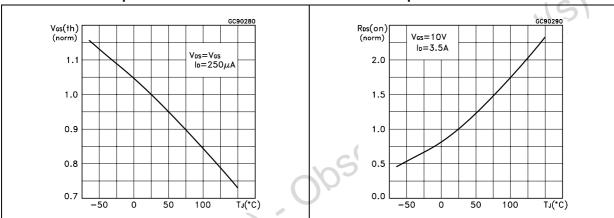
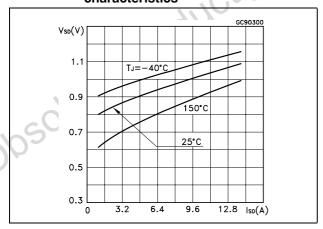


Figure 11. Source-drain diode forward characteristics



Test circuit STQ1NE10L

3 Test circuit

Figure 12. Switching times test circuit for resistive load

Figure 13. Gate charge test circuit

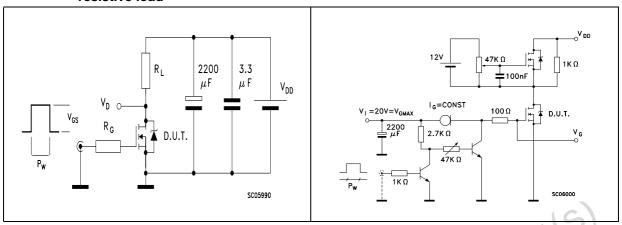


Figure 14. Test circuit for inductive load switching and diode recovery times

Figure 15. Unclamped Inductive load test circuit

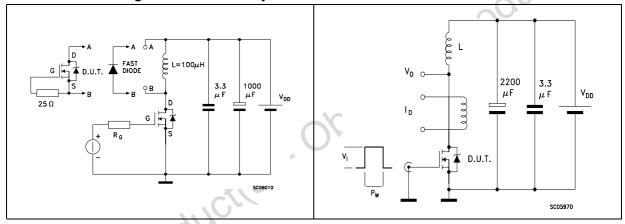
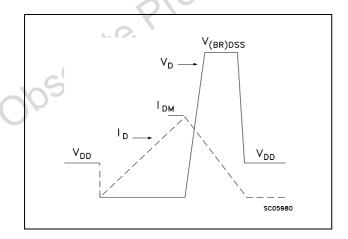


Figure 16. Unclamped inductive waveform



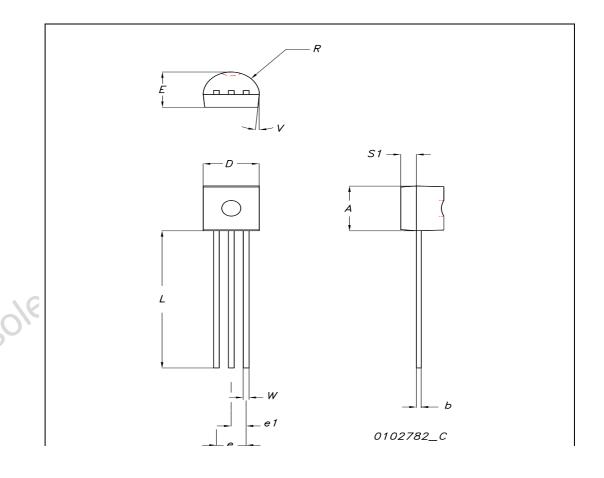
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

Obsolete Product(s). Obsolete Product(s)

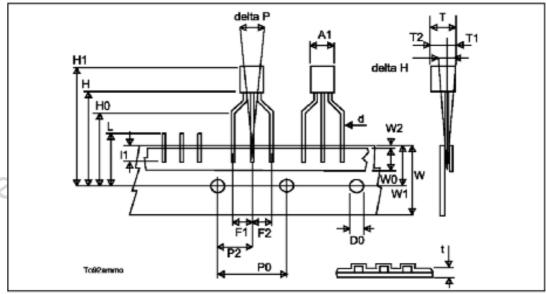
TO-92 MECHANICAL DATA

DIM.		mm.			inch	
DIWI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.32		4.95	0.170		0.194
b	0.36		0.51	0.014		0.020
D	4.45		4.95	0.175		0.194
Е	3.30		3.94	0.130		0.155
е	2.41		2.67	0.094		0.105
e1	1.14		1.40	0.044		0.055
L	12.70		15.49	0.50		0.610
R	2.16		2.41	0.085		0.094
S1	0.92		1.52	0.036		0.060
W	0.41		0.56	0.016		0.022
V		5°			5°	



TO-92 AMMOPACK

DIM.		mm.	m.		inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A1			4.8			0.19
Т			3.8			0.15
T1			1.6			0.06
T2			2.3			0.09
d			0.48			0.02
P0	12.5	12.7	12.9	0.49	0.5	0.51
P2	5.65	6.35	7.05	0.22	0.25	0.27
F1, F2	2.44	2.54	2.94	0.09	0.1	0.11
delta H	-2		2	-0.08		0.08
W	17.5	18	19	0.69	0.71	
W0	5.7	6	6.3	0.22	0.23	0.24
W1	8.5	9	9.25	0.33	0.35	0.36
W2			0.5			0.02
Н	18.5		20.5	0.72		0.80
HO	15.5	16	16.5	0.61	0.63	0.65
H1			25			0.98
D0	3.8	4	4.2	0.15	0.157	0.16
t			0.9			0.035
L			11			0.43
l1	3			0.11		
delta P	-1		1	-0.04		0.04



Revision history STQ1NE10L

5 Revision history

Table 6. Revision history

Date	Revision	Changes
21-Jun-2004	3	Complete version
31-Oct-2006	4	Document has been reformatted
31-Jan-2007	5	Typo mistake on <i>Table 1</i> .

Obsolete Product(s) - Obsolete Product(s)

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